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Transient Photoluminescence in MoS₂ layered crystals TUNG-WU HSIEH, CHIH-WEI LAI, Michigan State University — We report sub-10-ps transient exciton photoluminescence (PL) in mechanically exfoliated few- and monolayered crystals of MoS₂. We characterize layered crystals with thickness of $\sim 1 \mu m$, 100 nm, 10nm, and down to few-layers on SiO2/Si and mica substrates using luminescence and Raman spectroscopy spectroscopy. A frequency shift of $\sim 2 \text{ cm}^{-1}$ is observed on sub-10-nm-thick samples for the in-plane E_{2q}^{1} and the out-of-plane A_{1g} Raman modes. The relative intensities of Stokes and Anti-Stokes Raman components are used to determine the lattice temperature under a laser excitation with a spot diameter of 1 μ m and an average power 0.5 to 20mW. PL spectra are measured for lattice temperatures from \sim 70K to 500K. We observe two groups of luminescence emissions with comparable peak intensities centered at 1.85eV (VIS) and 1.35eV for samples of a thickness 1 μ m down to 10 nm under a cw laser excitation at a wavelength of 532nm (2.33eV). The VIS luminescence emissions are enhanced under a 2-ps pulsed laser excitation at a wavelength of 633nm (1.96eV). The rise and decay times of the luminescence are found to be less than 5 ps. Our results suggest that excitonic effects play a role in enhancing the luminescence quantum efficiency.

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